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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Cécile AULNETTE et al.

Confirmation No.: 7888

Application No: 10/763,978

Group Art Unit: 2811

Filing Date: January 22, 2004

Examiner:

For: SEMICONDUCTOR STRUCTURE FOR
PROVIDING STRAINED CRYSTALLINE LAYER ON
INSULATOR AND METHOD FOR FABRICATING
SAME

Atty. Docket No.: 4717-7300

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450
Sir:

Pursuant to applicants' duty of disclosure under 37 C.F.R. 1.56, enclosed is a Form PTO-1449 listing (1) reference for the Examiner's review and consideration. This reference was brought to the attention of the applicant and a copy is enclosed.

It is respectfully requested that this reference be made of record in this application by the Examiner's completion and return of the PTO Form 1449.

No fee is believed to be due for the filing of this statement as it is being submitted prior to an initial office action for this application. Should any fees be required, however, please charge such fees to Winston & Strawn LLP Deposit Account No. 50-1814.

Respectfully submitted,

Date: 2/17/05

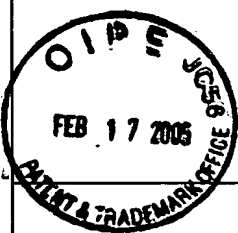
Allan A. Fanucci

Allan A. Fanucci (Reg. No. 30,256)

WINSTON & STRAWN LLP
CUSTOMER NO. 28765
(212) 294-3311

Enclosures

NY:866179.1

LIST OF REFERENCES CITED BY APPLICANT <i>(Use several sheets if necessary)</i>				ATTY. DOCKET NO.: 4717-7300		APPLICATION NO.: 10/763,978	
				APPLICANT: Cecile AULNETTE et al.			
				FILING DATE: January 22, 2004		GROUP: 2811	
U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
							YES NO
	AD	TW512487 English Abstract	12/2002	Taiwanese			X
	AE						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)							
	AF						
	AG						
	AH						
EXAMINER				DATE CONSIDERED			
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609 ; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							